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LABORATORY LOCATION/ CENTRAL OFFICE:	Reliability Engineering Test & Analysis Laboratory, OSRAM Opto Semiconductor (M) Sdn. Bhd. Trade Zone, Phase 1, Bayan Lepas 11900 Bayan Lepas, Pulau Pinang , 11900, PULAU PINANG MALAYSIA
	
ACCREDITED SINCE :	06 APRIL 2025
FIELD(S) OF TESTING:	ELECTRICAL MECHANICAL

This laboratory has demonstrated its technical competence to operate in accordance with MS ISO/IEC 17025:2017 (ISO/IEC 17025:2017).

This laboratory's fulfillment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and management system requirements that are necessary for it to consistently deliver technically valid test results and calibrations. The management system requirements in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001 (see Joint ISO-ILAC-IAF Communiqué dated April 2017).

CENTRAL LOCATION:	Reliability Engineering Test & Analysis Laboratory, OSRAM Opto Semiconductor (M) Sdn. Bhd. Trade Zone, Phase 1, Bayan Lepas 11900 Bayan Lepas, Pulau Pinang , 11900, Pulau Pinang
FIELD(S) OF TESTING :	ELECTRICAL, MECHANICAL

SCOPE OF TESTING : ELECTRICAL

Material / Product Tested	Type Of Test / Properties Measured / Range Of Measurement	Standard Test Methods / Equipment / Techniques
Led, Detector	Electrical Characteristics: 1. Forward voltage characteristics: 200 mV to 100V 2. Reverse current characteristic: 100 nA to 10 A Electrostatic Discharge (Human Body Model)	In-house method A66762-D0500-D273-*-7681 CIE 127 ANSI/ESDA/JEDEC JS-001

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Material / Product Tested	Type Of Test / Properties Measured / Range Of Measurement	Standard Test Methods / Equipment / Techniques
	Electrical Characteristics: 1. Forward voltage characteristics: 200 mV to 100V 2. Reverse current characteristic: 100 nA to 10 A	In-house method A66762-D0500-D273-*-7681
Led	Optical Characteristics 1. Wavelength: 200 nm to 800 Nm 2. Luminous intensity (Iv) 0.1 mcd to 2000 cd 3. Luminous flux (Φ _{av}) 0.0001 lm to 100 000 lm 4. Color coordinate X, Y 0.2 to 0.5	CIE 127

SCOPE OF TESTING : MECHANICAL

Material / Product Tested	Type Of Test / Properties Measured / Range Of Measurement	Standard Test Methods / Equipment / Techniques
Led, Detector	Resistance to soldering heat (Reflow) Solderability	JESD22-A113 IEC 61760-1 Clause 6 IEC 60068-2-20 Clause 4 IEC 60068-2-58 Method 1 (SMD only). Clause 6 EIA/IPC/JEDEC J-STD-002
	Scanning Electron Microscope (SEM) – imaging and measurement/ evaluation	In-house method A66762-D0500-D166-*-7681
	Energy Dispersive X-Ray Analysis (EDX) – qualitative elemental analysis: BE to U	In-house method A66762-D0500-D122-*-7681
	X-Ray Transmission Analysis (X-ray) – imaging & Evaluation	A66762-D0500-D093-*-7681
	Focused Ion Beam (FIB) – imaging and evaluation	A66762-D0500-D250-*-7681

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Material / Product Tested	Type Of Test / Properties Measured / Range Of Measurement	Standard Test Methods / Equipment / Techniques
Environmental Led, Detector	Temperature and Humidity Bias Temperature and Humidity Reverse Bias Temperature and Humidity Storage High Temperature Storage Temperature Cycling (Air) Power Temperature Cycle Thermal Shock (Liquid) High Temperature Reverse Bias Steady State Life Test Pulse Life Test Highly Accelerated Temperature and Humidity Stress Test (HAST) Accelerated Moisture Resistance-Unbiased Autoclave (Pressure Cooker Test (PCT)) Damp Heat Cyclic (DHC) Composite Temperature/Humidity Cyclic Test (CTHC)	JESD22-A101 IEC 60068-2-67 JESD22-A101 IEC 60068-2-78 JESD22-A101 JESD22-A103E.01 Condition A & B IEC 60068-2-2 JESD22-A104 JESD22-A105D; Method A & B JESD22-A106 IEC 60068-2-14; Test N JESD22-A108 JESD22-A108 JESD22-A108 JESD22-A110 JESD22-A102 IEC 60068-2-30 IEC 60068-2-38

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